

Atal Bihari Vajpayee Indian Institute of Information Technology & Management, Gwalior

EE404: Integrated Circuit Technology

Major Examination (Session 2024–25)

Maximum Time: 3 Hours Max Marks: 70

Note: All questions are compulsory. Answers should be precise and well supported with diagrams.

- 1. (a) Explain wafer cleaning and preparation methods. (b) Discuss the importance of crystal orientation in IC fabrication. (10 Marks)
- 2. (a) Compare diffusion and ion implantation techniques with neat diagrams. (b) Discuss advantages and limitations of each. (10 Marks)
- 3. (a) Derive the small-signal model of MOSFET. (b) Explain the short-channel effects observed in modern MOS devices. (12 Marks)
- 4. (a) Explain photolithography steps in detail. (b) Why is resolution enhancement critical for sub-10nm technology nodes? (12 Marks)
- 5. (a) Describe different metallization techniques used in ICs. (b) Compare aluminum interconnects with copper interconnects. (10 Marks)
- 6. Short Notes (any three): (i) Silicon-on-Insulator (SOI) (ii) Shallow Trench Isolation (STI) (iii) FinFET technology (iv) Role of Packaging in IC performance (12 Marks)
- 7. Case Study: A fabrication unit is shifting from 90nm to 28nm process technology. Highlight the fabrication challenges, device performance improvements, and reliability concerns.

 (4 Marks)